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Substitute for form 1449A/PTO	Complete if Known
	Application Number
INFORMATION DISCLOSURE	Filing Date 03/30/2004
STATEMENT BY APPLICANT	First Named Inventor Purch Martin W.
	VAn Unit
(Use as many sheets as necessary)	Examiner Name
CSheet 125 Sept.	Attorney Docket Numbers 22802:169US18AMS@662

				U. S. PATENT I	DOCUMENTS	
Examiner Initials*	Cite No. <sup>1</sup>	Num	ocument Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
M		US-	6,440,211	08/27/2002	David Beach et al.	
		US-	6,537,689	03/25/2003	Schoop, Urs, et al.	
		US-	6,562,761	05/13/2003	Fritzemeier, L, et al.	
		US-	6,617,283	09/09/2003	Paranthaman, M., et a	
		US-	6,027,564	02/22/2000	Fritzemeir, L., et al.	
160		US-	6,537,689	03/25/2003	Schoop, et al.	
12		US-	6,077,344	06/20/2000	Schoup, S., et al.	
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	FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	١.
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Substitute for form 1449B/PTO		Complete if Known
	Application Number	
information disclosure	Filing Date	03/30/2004
STATEMENT BY APPLICANT	First Named Inventor	Rupich, Martin W
	Art Unit	
(Use as many sheets as necessary)	Examiner Name	
Sheet 2 2 vof 22	Attorney Docket Number	2802-169USTAMSC-662 334

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
O		LEE, DOMINIC F., et al., Alternative Buffer Architectures for High Critical Current Density YBCO Superconducting Deposits on Rolling Assisted Biaxially-Textured Substrates, Jpn. J. Appl. Phys., Vol. 38, (Feb. 1999), 178-180	
		BEACH, DAVID B., et al., Sol-Gel Synthesis of Rare Earth Aluminate Films as Buffer Layers for High Tc Superconducting Films, Mat. Res. Soc. Symp. Proc., Vol. 495 (1998), 263-276	
		PARANTHAMAN, M., et al., Growth of Biaxially Textured RE2O3 Buffer Layers on Rolled-Ni Substrates Using Reactive Evaporation for HTS-Coated Conductors, Supercond. Sci. Technol. 12 (1999) 319-325	
		WU, X., et al., Properties of YBa2Cu3O7-8 Thick Films on Flexible Buffered Metallic Substrates, Appl. Phys. Lett. 67 No.6:2397 (Oct. 1995),	
		SHOUP, S., et al., Epitaxial Thin Film Growth of Lanthanum and Neodymium Aluminate Films on Roll-Textured Nickel Using a Sol-Gel Method, J. Am. Cer. Soc., Vol. 81, 3019-3021 (1998)	
		RUPICH, M., et al., Growth and Characterization of Oxide Buffer Layers for YBCO Coated Conductors, I.E.E.E. Trans. on Appl. Supercon., Vol. 9, (1999) 1527-1530	
		CELIK, E., et al., Processing Dependence of Texture Development in La2Zr2O7 Buffer Layer by Sol-Gel Technique for YBCO Coated Conductors, Vol. 48 (2002) 503-510, Proc. Intl. Cryo. Mats. ConfICMC	
		JACOBSEN, S., et al., Sharp Microfaceting of (001)-Oriented Cerium Dioxide Thin Films and the Effect of Annealing on Surface Morphology, Surface Science 429 (1999)	
)/		JACOBSEN, S., et al., Epitaxial cerium oxide buffer layers and YBa2Cu3O7-8 thin films for microwave device applications, J. Mater. Res., Vol. 14, No. 6 (June 1999) 2385-2393	******
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